§ 90.322 Calibration of other equipment.

Calibrate other test equipment used for testing as often as required by the test equipment manufacturer or as necessary according to good engineering practice.

§ 90.323 Analyzer bench checks.

(a) Prior to initial use and after major repairs, verify that each analyzer complies with the specifications given in Table 2 in Appendix A of this subpart.

(b) If a stainless steel NO₂ to NO converter is used, condition all new or replacement converters. The conditioning consists of either purging the converter with air for a minimum of four hours or until the converter efficiency is greater than 90 percent. The converter must be at operational temperature while purging. Do not use this procedure prior to checking converter efficiency on in-use converters.

§ 90.324 Analyzer leakage check.

(a) Vacuum side leak check. (1) Check any location within the analysis system where a vacuum leak could affect the test results.

(2) The maximum allowable leakage rate on the vacuum side is 0.5 percent of the in-use flow rate for the portion of the system being checked. The analyzer flows and bypass flows may be used to estimate the in-use flow rates.

(3) The sample probe and the connection between the sample probe and valve V2, see Figure 1 in Appendix B of subpart E of this part, may be excluded from the leak check.

(b) Pressure-side leak check. Substantial leaks of the sample on the pressure side of the system may impact sample integrity if the leaks are of sufficient magnitude. As a safety precaution, good engineering practice would require that manufacturers perform periodic pressure-side leak checks of the sampling system. The recommended maximum leakage rate on the pressure side is five percent of the in-use flow rate.

[60 FR 34598, July 3, 1995, as amended at 70 FR 40449, July 13, 2005]

§ 90.325 Analyzer interference checks.

(a) Gases present in the exhaust other than the one being analyzed can interfere with the reading in several ways. Positive interference occurs in NDIR and PMD instruments when the interfering gas gives the same effect as the gas being measured, but to a lesser degree. Negative interference occurs in NDIR instruments by the interfering gas broadening the absorption band of the measured gas, and in CLD instruments by the interfering gas quenching the radiation. The interference checks described in this section are to be made initially and after any major repairs that could affect analyzer performance.

(b) CO analyzer water and CO₂ interference checks. Bubble through water at room temperature a CO₂ span gas having a concentration of between 80 percent and 100 percent inclusive of full scale of the maximum operating range used during testing and record the analyzer response. For dry measurements, this mixture may be introduced into the sample system prior to the water trap. The analyzer response must not be more than one percent of full scale for ranges equal to or above 300 ppm or more than three ppm for ranges below 300 ppm.

(c) NOₓ analyzer quench check. The two gases of concern for CLD (and HCLD) analyzers are CO₂ and water vapor. Quench responses to these two gases are proportional to their concentrations and, therefore, require test techniques to determine quench at the highest expected concentrations experienced during testing.

(i) NOₓ analyzer CO₂ quench check. (i) Pass a CO₂ span gas having a concentration of 80 percent to 100 percent of full scale of the maximum operating range used during testing through the CO₂ NDIR analyzer and record the value “a.”

(ii) Dilute the CO₂ span gas approximately 50 percent with NO span gas and pass through the CO₂ NDIR and CLD (or HCLD). Record the CO₂ and NO values as “b” and “c” respectively.

(iii) Shut off the CO₂ and pass only the NO span gas through the CLD (or HCLD). Record the NO value as “d.”

(iv) Calculate the percent CO₂ quench as follows, not to exceed three percent:
\[
\% \text{ CO}_2 \text{ quench} = 100 \times \left( 1 - \frac{(c \times a)}{(d \times a) - (d \times b)} \right) \times \left( \frac{a}{b} \right)
\]

Where:
- \(a\) = Undiluted CO\(_2\) concentration (percent)
- \(b\) = Diluted CO\(_2\) concentration (percent)
- \(c\) = Diluted NO concentration (ppm)
- \(d\) = Undiluted NO concentration (ppm)

(2) \(\text{NO}_x\) analyzer water quench check.

(i) This check applies to wet measurements only. An NO span gas having a concentration of 80 percent to 100 percent of full scale of a normal operating range is passed through the CLD (or HCLD) and the response recorded as ‘‘D’’. The NO span gas is then bubbled through water at room temperature and passed through the CLD (or HCLD) and the analyzer’s response recorded as AR. Determine and record the analyzer’s absolute operating pressure and the bubbler water temperature. (It is important that the NO span gas contains minimal NO\(_2\) concentration for this check. No allowance for absorption of NO\(_2\) in water has been made in the following quench calculations.)

(ii) Calculations for water quench must consider dilution of the NO span gas with water vapor and scaling of the water vapor concentration of the mixture to that expected during testing. Determine the mixture’s saturated vapor pressure (designated as Pwb) that corresponds to the bubbler water temperature. Calculate the water concentration (‘‘Z1’’, percent) in the mixture by the following equation:

\[
Z_1 = 100 \times \frac{\text{Pwb}}{\text{GP}}
\]

where GP is the analyzer’s standard operating pressure (pascals).

(iii) Calculate the expected dilute NO span gas and water vapor mixture concentration (designated as D1) by the following equation:

\[
D_1 = D \times \left( 1 - \frac{Z_1}{100} \right)
\]

§ 90.327 Sampling system requirements.

(a) Sample component surface temperature. For sampling systems which use heated components, use engineering judgment to locate the coolest portion of each component (pump, sample line section, filters, and so forth) in the heated portion of the sampling system that has a separate source of power or heating element. Monitor the temperature at that location. If several components are within an oven, then only the surface temperature of the component with the largest thermal mass and the oven temperature need be measured.